

Digital Pulse Shape methods with Silicon Detectors

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for the NUCL-EX and FAZIA collaborations



Why Pulse Shape in Silicon – comparison with $\Delta E-E$



Experimental results with analog methods



Digital signal processing:

- Energy measurements
- Timing and Time of Flight measurements
- Pulse Shape Analysis



Key factors affecting PSA

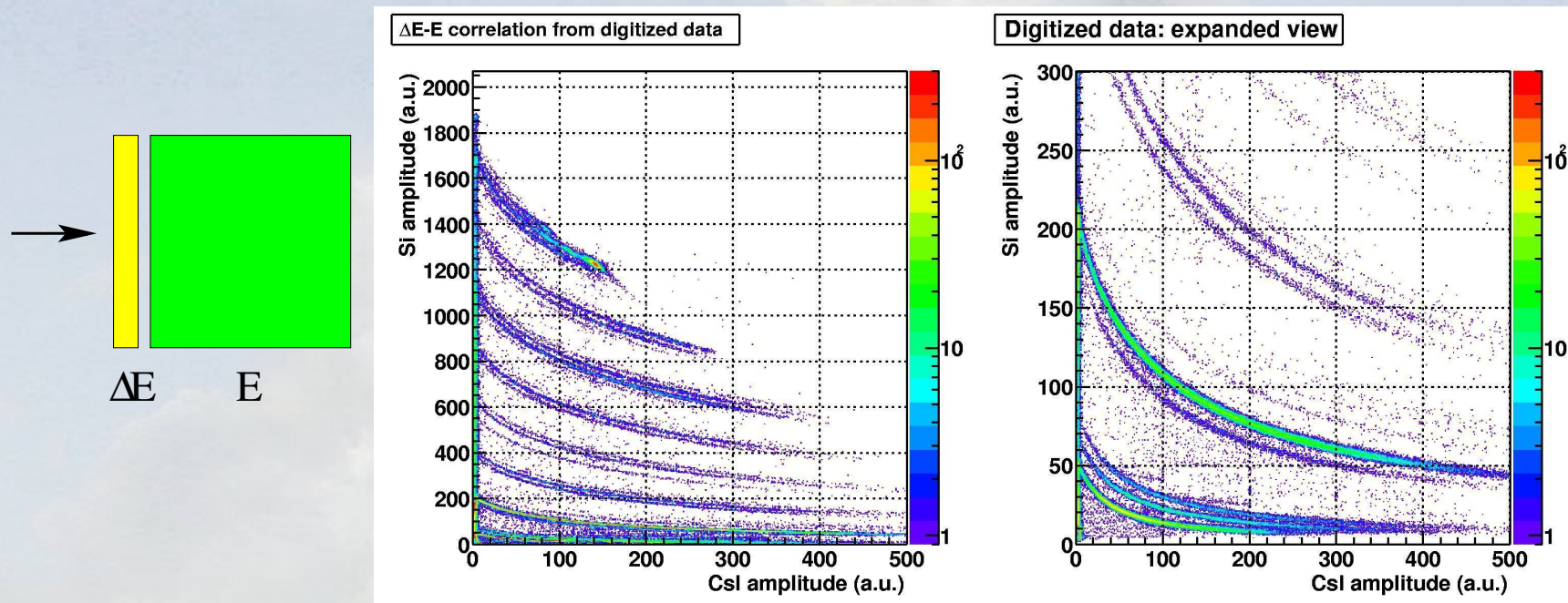


Current research topics within FAZIA



Conclusions

The ΔE -E method is a very common particle identification solution:



L.Bardelli *et al.*, Nucl.Phys. **A746** (2004) 272.

Problem: high thresholds \leftrightarrow punch through ΔE

Some estimates about thresholds and isotopic identification properties for a ΔE -E detector, taking into account energy straggling and homogeneity ($\pm 0.5 \mu\text{m}$):

300 μm detector:

| Ion | Threshold | Near punch through: | |
|-----------------|-----------|-------------------------------------|---|
| | | $\Delta E(Z, A+1) - \Delta E(Z, A)$ | $\delta E(\text{stragg} + \text{unif})$ |
| ^1H | 6.2 AMeV | | |
| ^4He | 6.2 AMeV | | |
| ^6Li | 7.8 AMeV | | |
| ^8Be | 9.1 AMeV | | |
| ^{10}B | 10.3 AMeV | | |
| ^{12}C | 11.4 AMeV | | |

Using Hubert eloss tables and Wang/Yang straggling parametrization

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| | | $\Delta E(Z, A+1) - \Delta E(Z, A)$ | $\delta E(\text{stragg} + \text{unif})$ |
| ^1H | 6.2 AMeV | 2.0 MeV | 0.5 MeV |
| ^4He | 6.2 AMeV | 2.4 MeV | 0.9 MeV |
| ^6Li | 7.8 AMeV | 3.0 MeV | 1.4 MeV |
| ^8Be | 9.1 AMeV | 3.6 MeV | 1.9 MeV |
| ^{10}B | 10.3 AMeV | 4.0 MeV | 2.4 MeV |
| ^{12}C | 11.4 AMeV | 4.5 MeV | 3.1 MeV |

Using Hubert eloss tables and Wang/Yang straggling parametrization

Some estimates about thresholds and isotopic identification properties for a ΔE -E detector, taking into account energy straggling and homogeneity ($\pm 0.5 \mu\text{m}$):

100 μm detector:

| Ion | Threshold | Near punch trough: | |
|-----------------|-----------|-------------------------------------|---|
| | | $\Delta E(Z, A+1) - \Delta E(Z, A)$ | $\delta E(\text{stragg} + \text{unif})$ |
| ^1H | 3.2 AMeV | 1.0 MeV | 0.3 MeV |
| ^4He | 3.2 AMeV | 1.1 MeV | 0.5 MeV |
| ^6Li | 4.0 AMeV | 1.4 MeV | 0.8 MeV |
| ^8Be | 4.7 AMeV | 1.7 MeV | 1.0 MeV |
| ^{10}B | 5.2 AMeV | 1.8 MeV | 1.4 MeV |
| ^{12}C | 5.8 AMeV | 1.8 MeV | 1.7 MeV |

Some estimates about thresholds and isotopic identification properties for a ΔE – E detector, taking into account energy straggling and homogeneity ($\pm 0.5 \mu\text{m}$):

50 μm detector:

| Ion | Threshold | Near punch trough: | |
|-----------------|-----------|-------------------------------------|---|
| | | $\Delta E(Z, A+1) - \Delta E(Z, A)$ | $\delta E(\text{stragg} + \text{unif})$ |
| ^1H | 2.1 AMeV | 0.6 MeV | 0.2 MeV |
| ^4He | 2.1 AMeV | 0.5 MeV | 0.3 MeV |
| ^6Li | 2.6 AMeV | 0.8 MeV | 0.6 MeV |
| ^8Be | 3.0 AMeV | 0.9 MeV | 0.7 MeV |
| ^{10}B | 3.4 AMeV | 1.0 MeV | 0.9 MeV |
| ^{12}C | 3.7 AMeV | 1.1 MeV | 1.2 MeV |



It is not possible to lower the identification thresholds by simply using thinner ΔE detectors, due to various experimental effects (mainly energy straggling and detector inhomogeneities).

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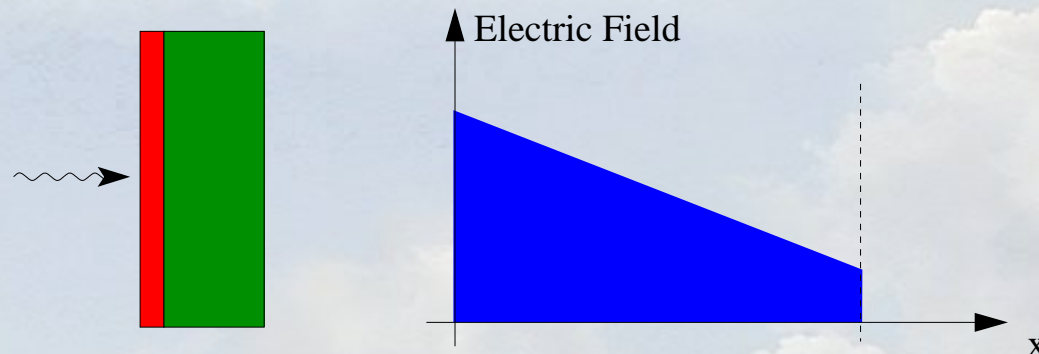
■  A more effective method: Pulse Shape in Silicon

PSA properties are due to two main effects:

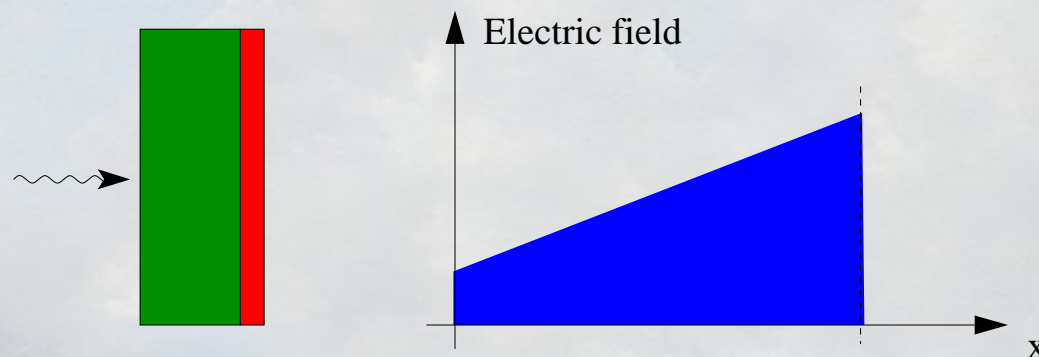
Electric field particles that explore high-electric-field regions will have shorter collection times

Plasma effects signals from high ionization-density tracks (heavy ions with small range) have a longer collection time (due to a “space-charge” effect)

Standard configuration



Reverse configuration



Increased
Pulse Shape
capabilities due to
a combination of
charge collection
and **plasma** effects.

reverse mount Silicon detector

Some groups (ChimeraPS) are also investigating PSA in front mount Si

Ions with different ranges in silicon will explore different regions of the detector, i.e. the charge collection time will vary.

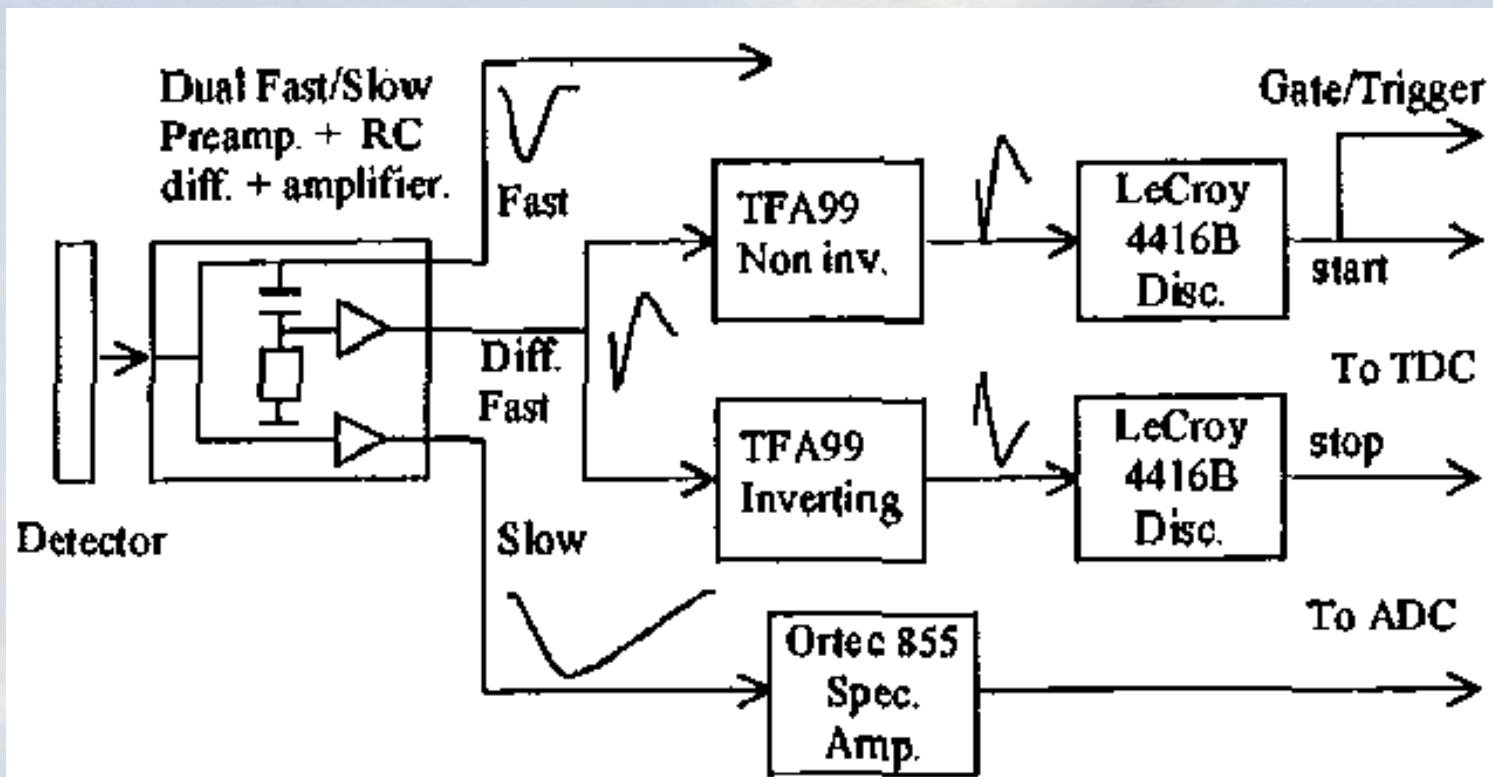
For reverse mount silicon:

Long range → Short collection time
Short Range → Long collection time

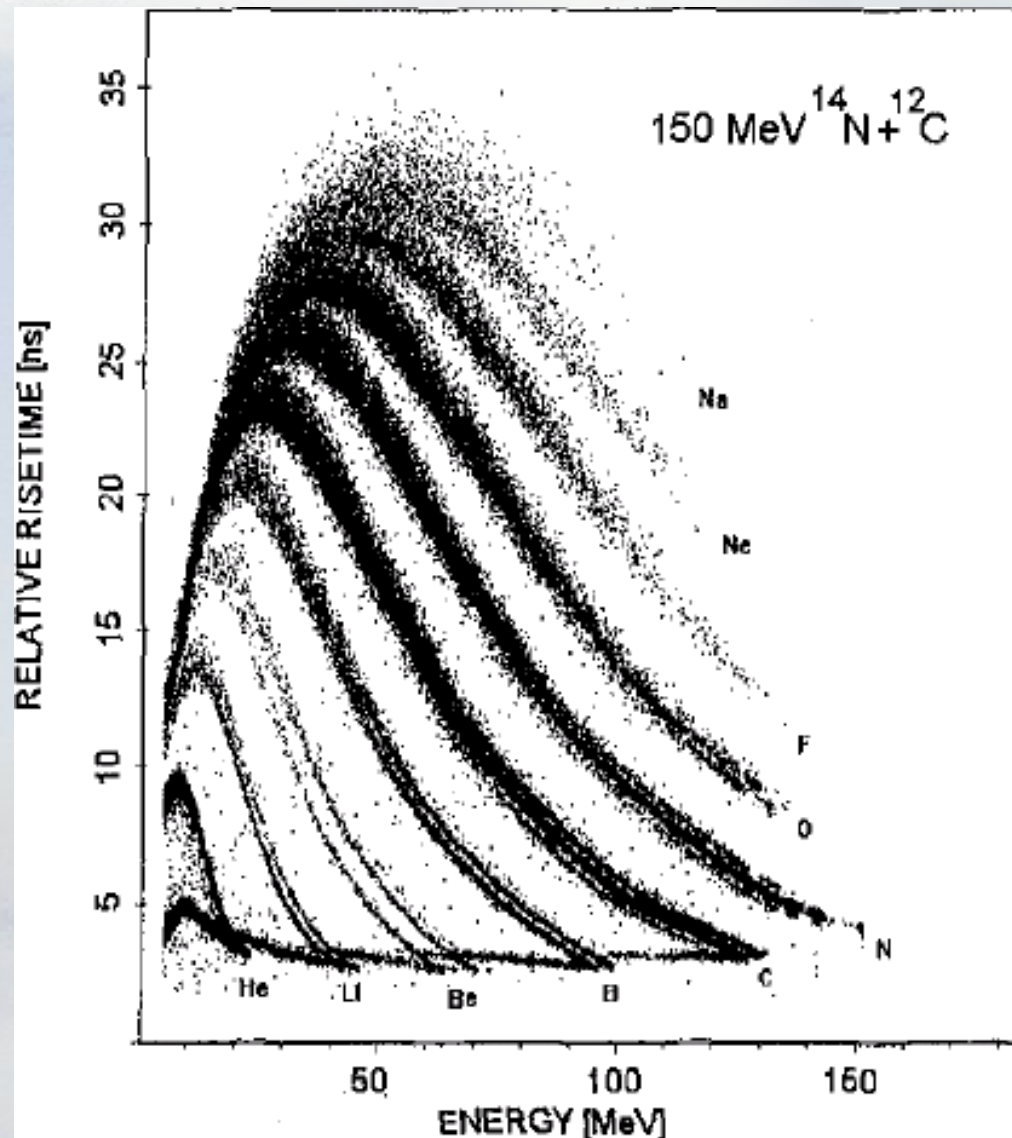
Idea: look an Energy vs “RiseTime” plot.

➡ Some results with analog methods:

Example of an analog chain employing energy and risetime measurements:

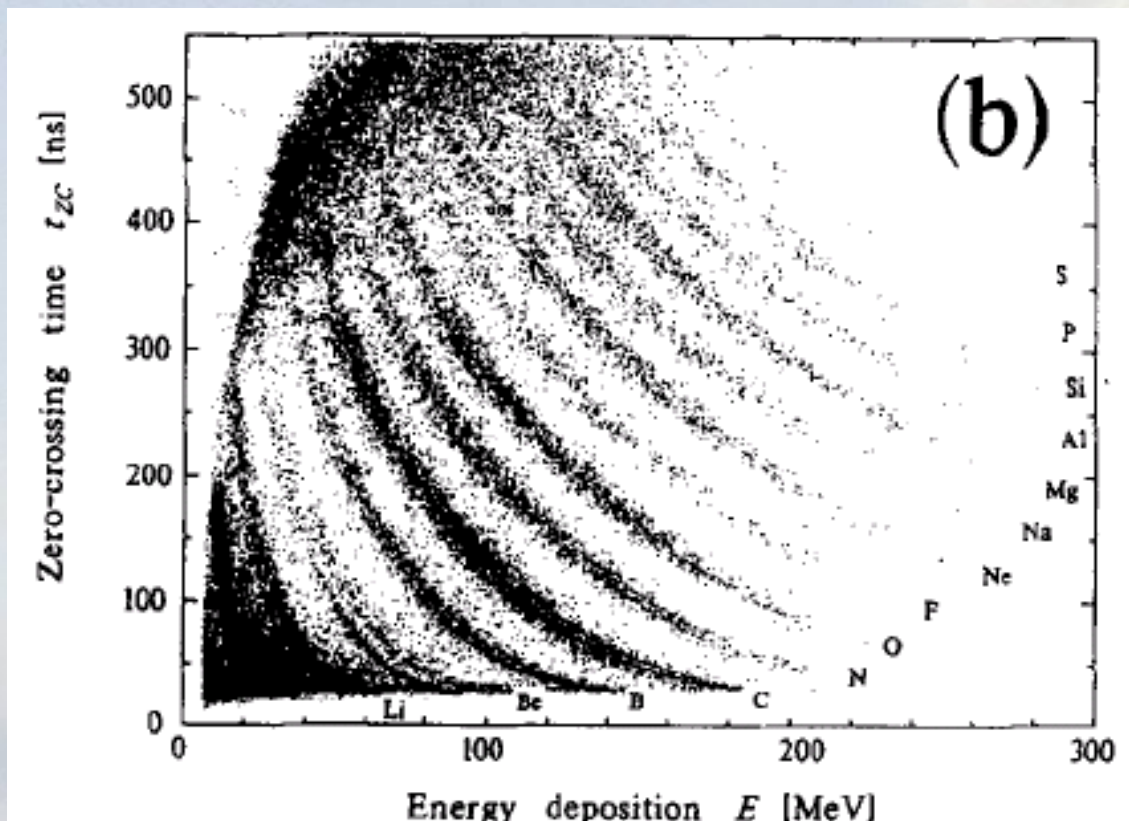


M.Mutterer *et al.*, IEEE Trans. Nucl. Science, vol.47, no.3, June 2000



250 μm NTD detector
100 mm²
Depletion: 45 V
Bias: 140 V

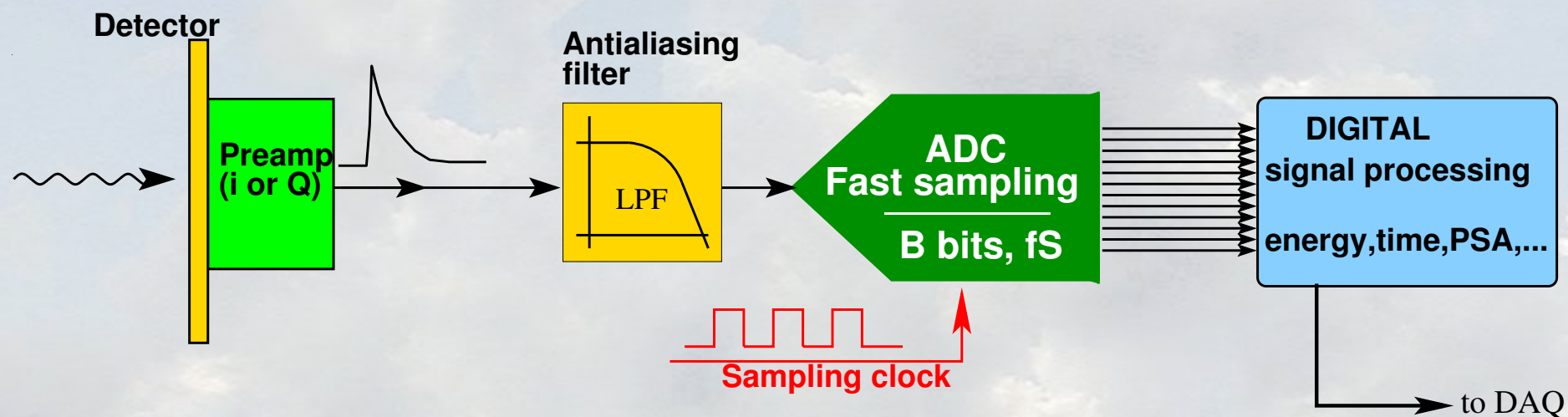
M.Mutterer *et al.*, IEEE Trans. Nucl.
Science, vol.47, no.3, June 2000

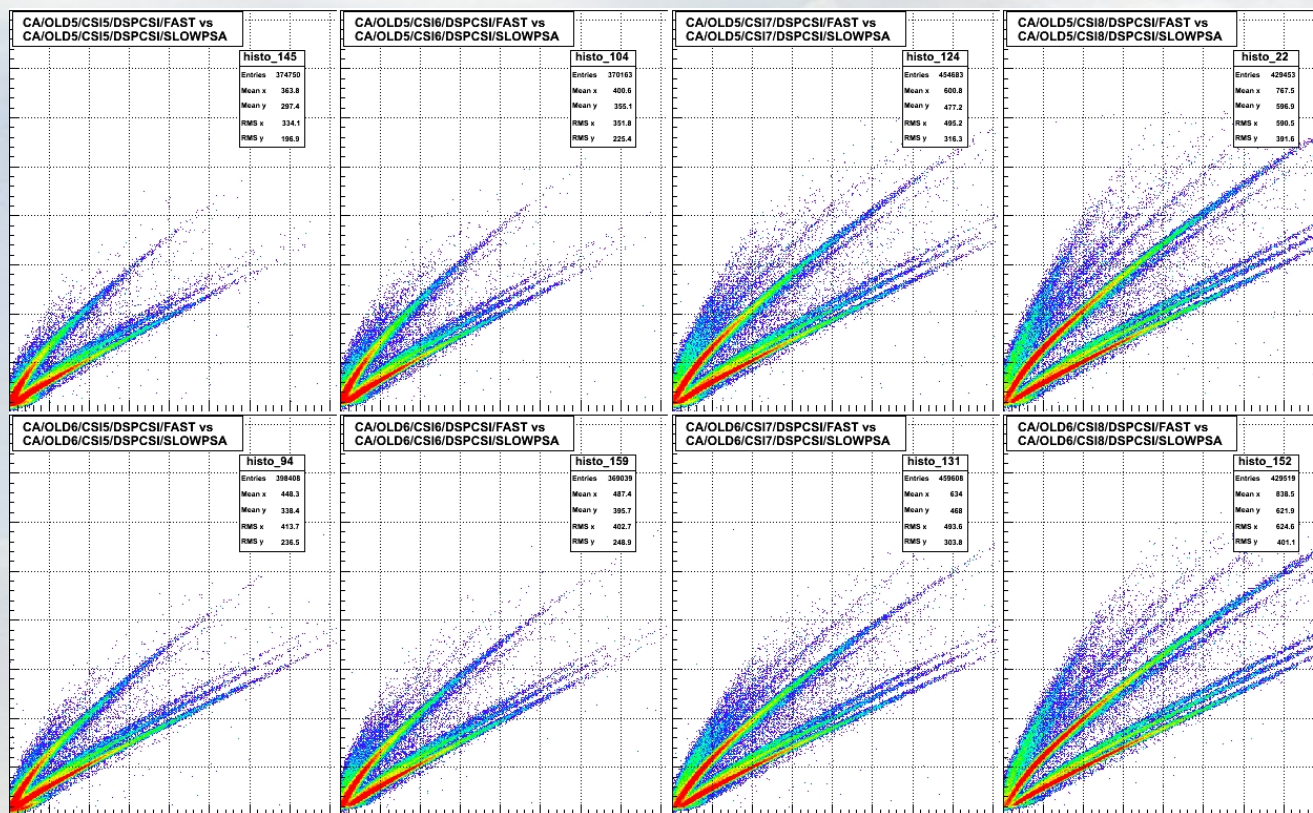


500 μm detector
750 mm^2
Depletion: 62 V
Bias: 80 V

G.Pausch *et al.*, Nucl. Instr. and Meth.
A365 (1995) 176

Typical configuration employing digital sampling and processing:





Fast-Slow correlations in CsI, GARFIELD experiment @ LNL
Custom digitizer 12 bit–125 MS/s, about 180 channels installed and tested, ~200 in construction

G.Pasquali *et al.*, NIMA 570 (2007) 126

What do we need to perform Nuclear Physics experiments with such digitizers?

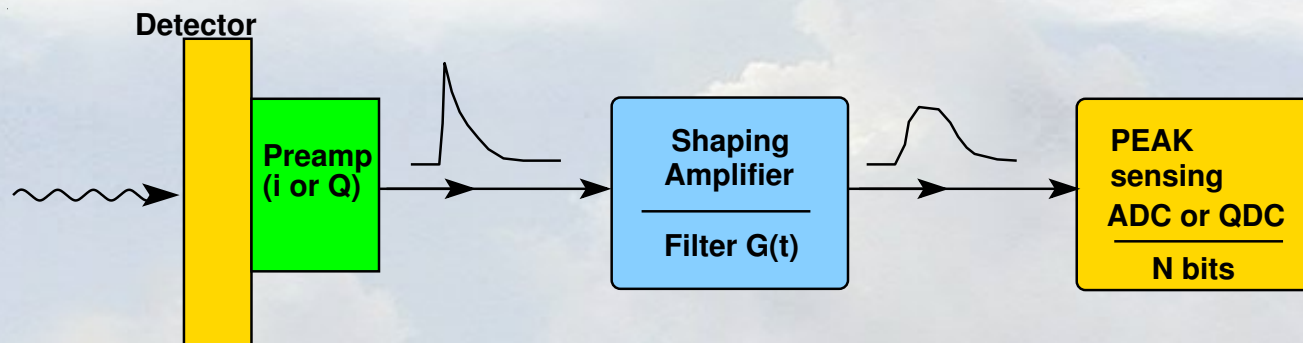
A wide class of detectors can be handled with:

- Signal Amplitude measurement (\Rightarrow energy)
- Timing measurement (\Rightarrow CFD, rise time)
- Inter-channel time synchronization (\Rightarrow ToF)
- Pulse Shape (often a combination of Amplitude and Timing)

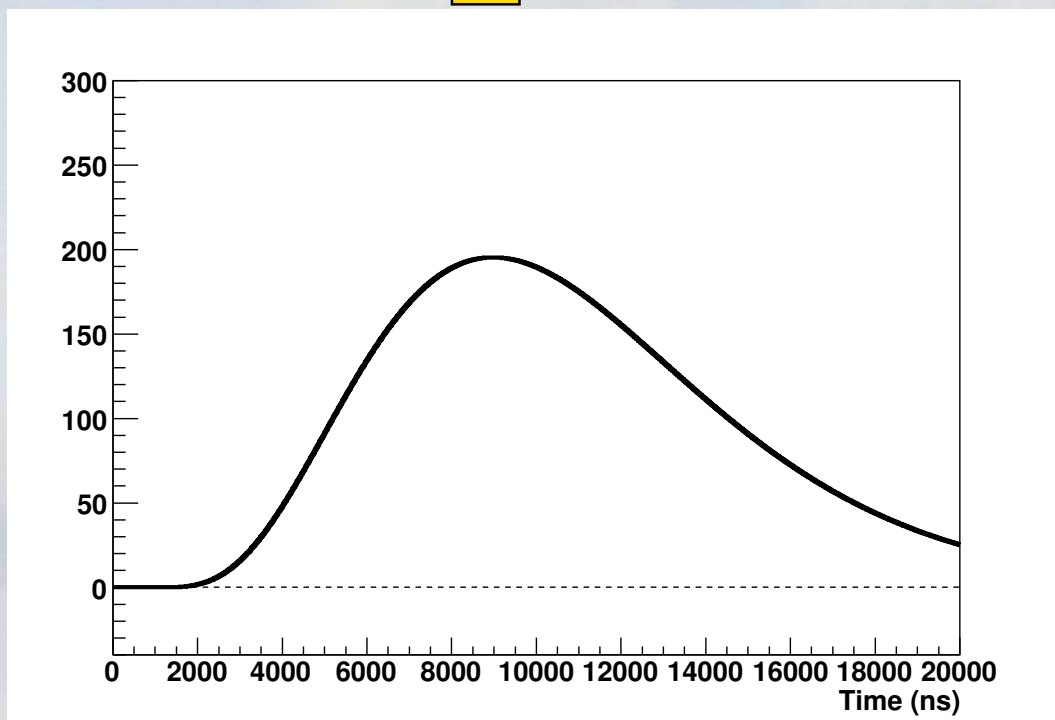
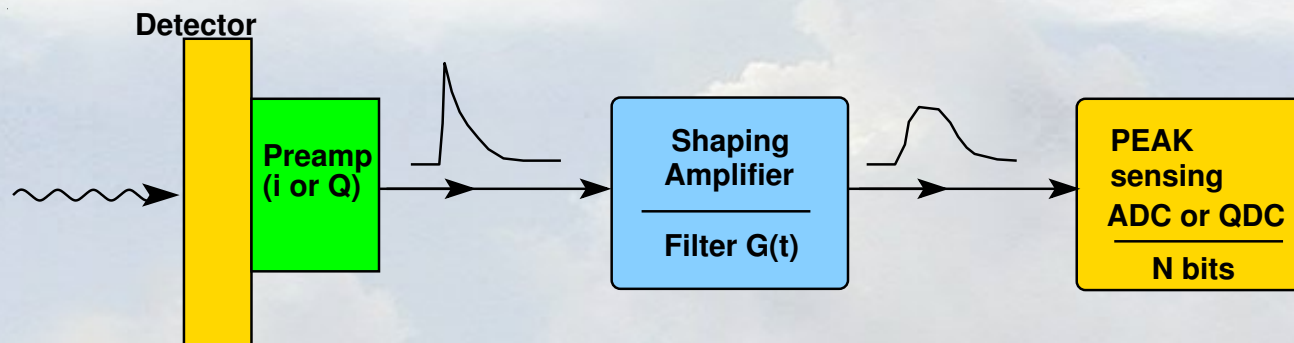
Let's see some examples...

energy

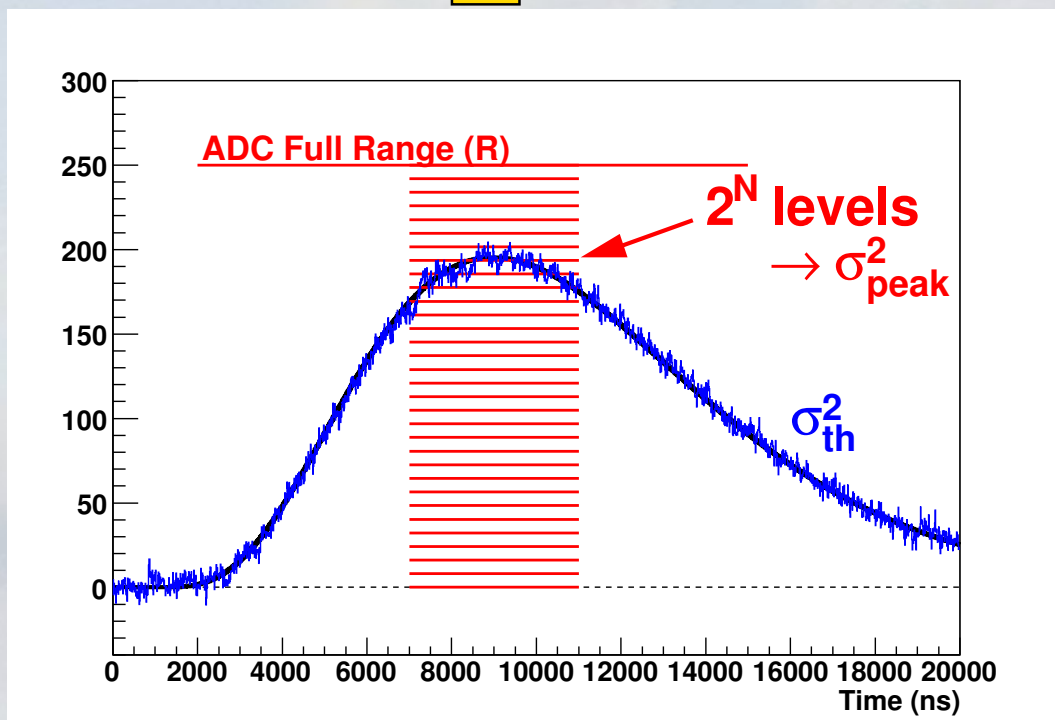
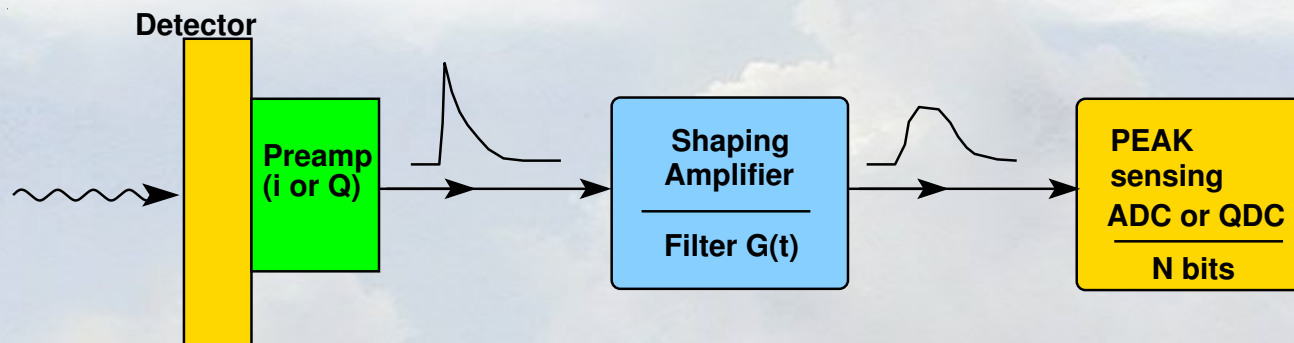
Energy measurements (analog world)



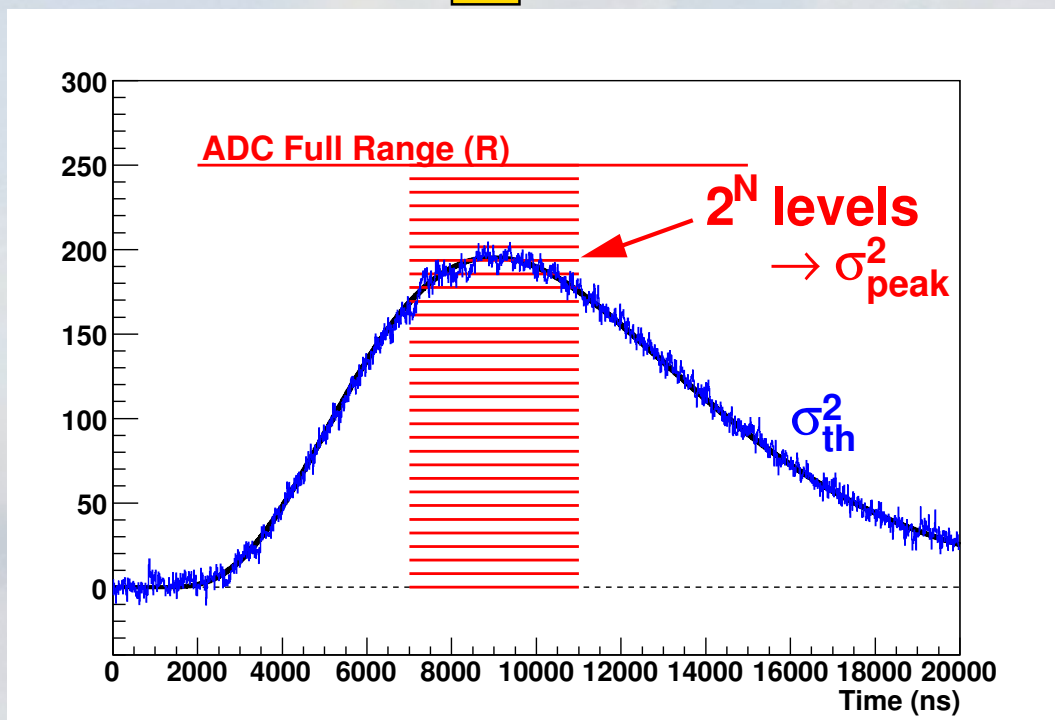
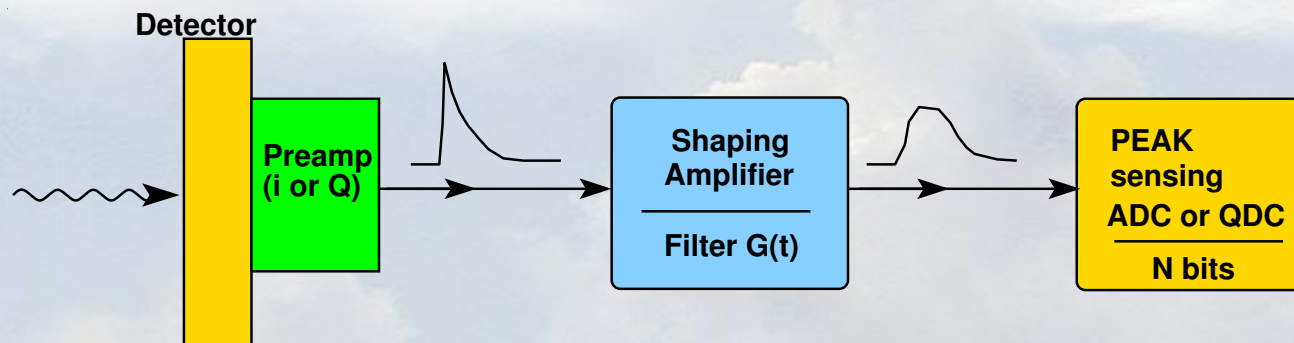
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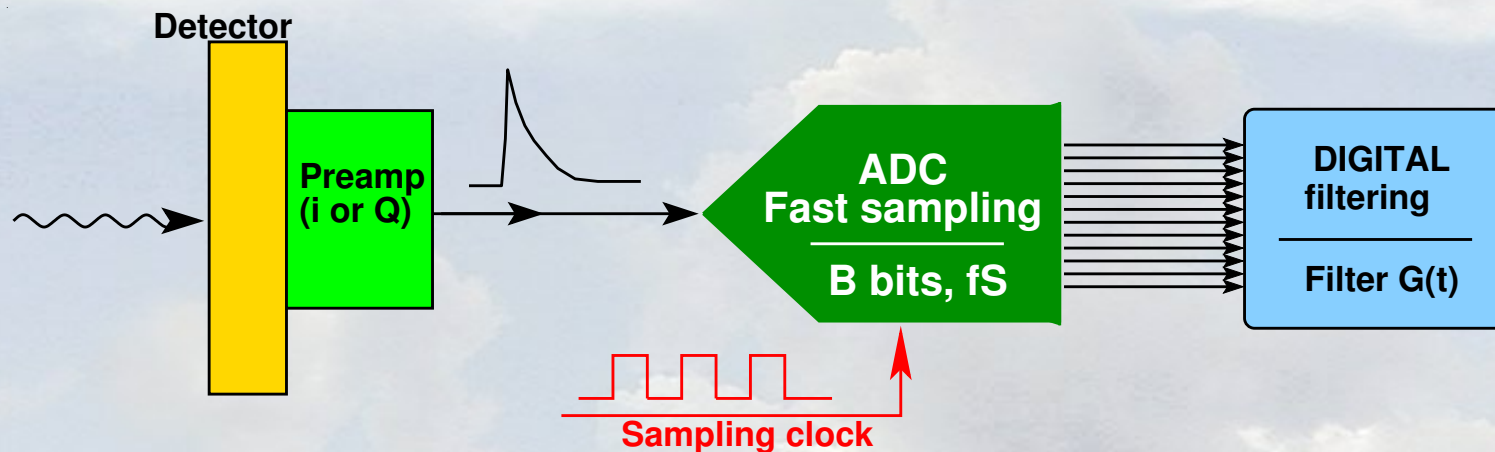
Energy measurements (analog world)



$$\sigma_{exp}^2 = \sigma_{th}^2 + \sigma_{peak}^2$$

PEAK-sensing
contribution to the
resolution:

$$\frac{\sigma_{exp}^2}{\sigma_{th}^2} = 1 + \frac{9}{12} \cdot \left(\frac{R}{3\sigma_{th}} \right)^2 \frac{1}{4^N}$$

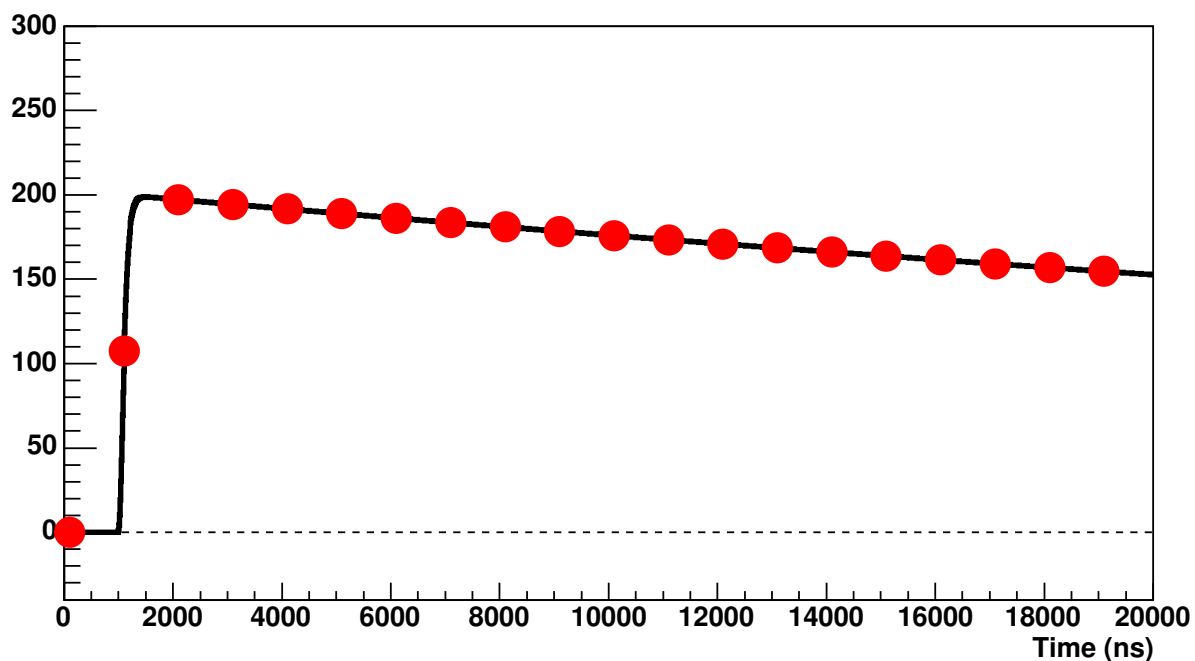
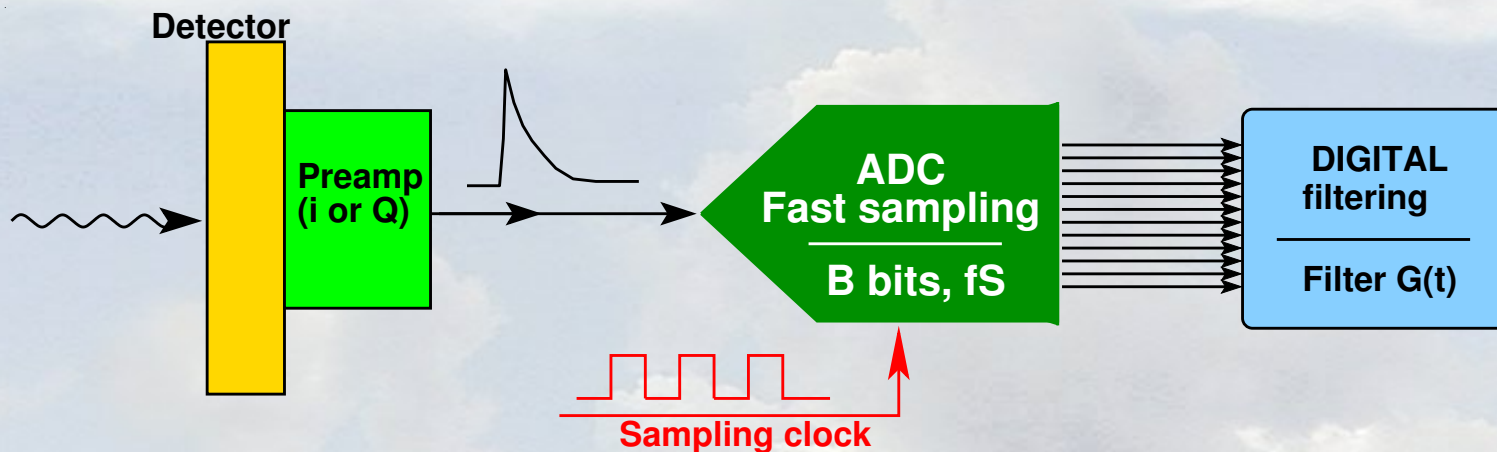


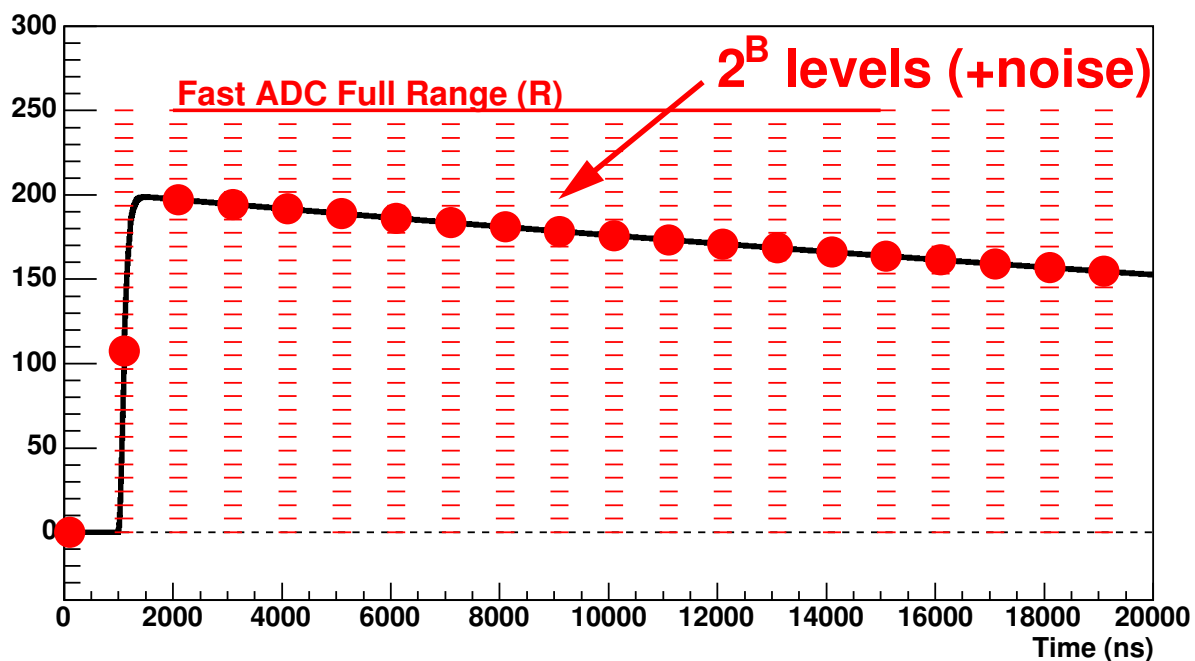
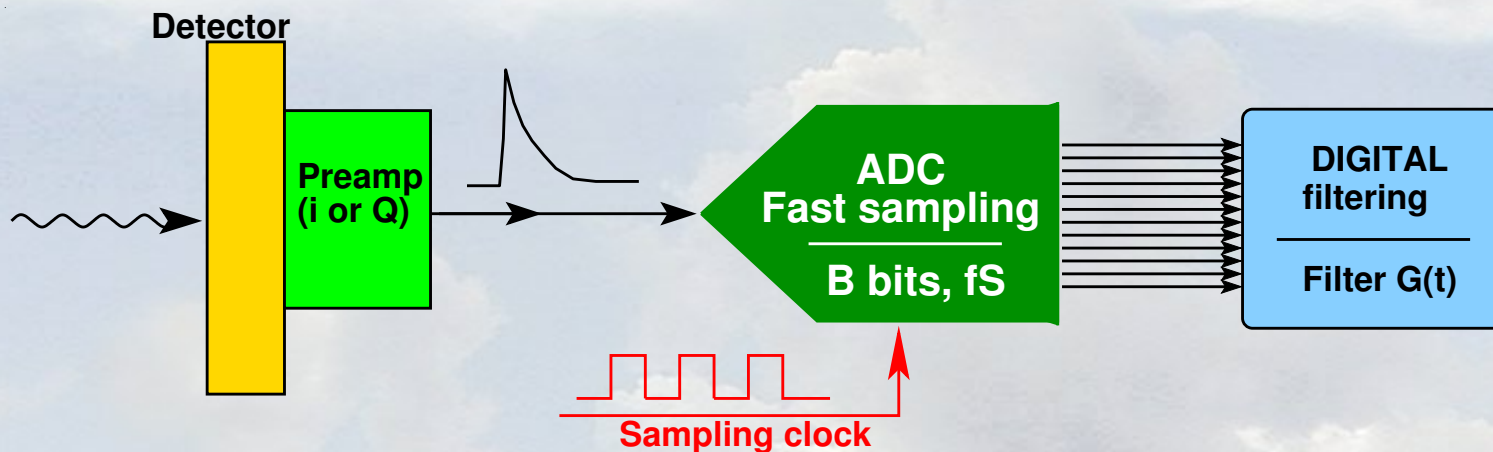
Which resolution with an
 B -bits, f_S -MSamples/s fast AD converter

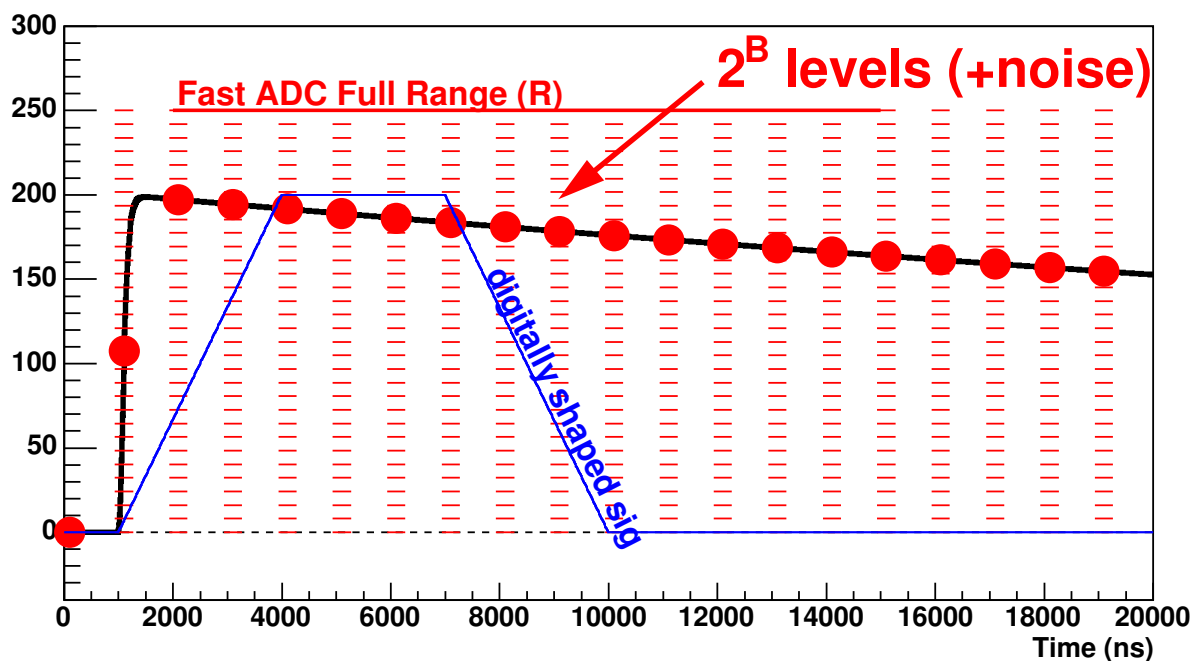
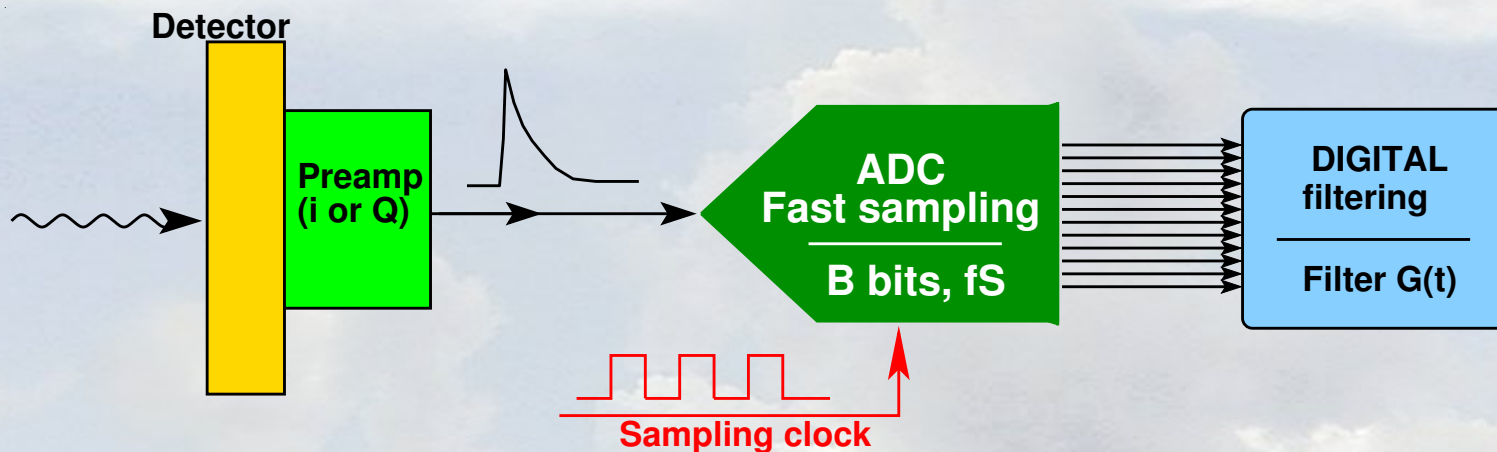
?

(direct comparison with peak-sensing ADCs?)

Energy measurements with digital systems





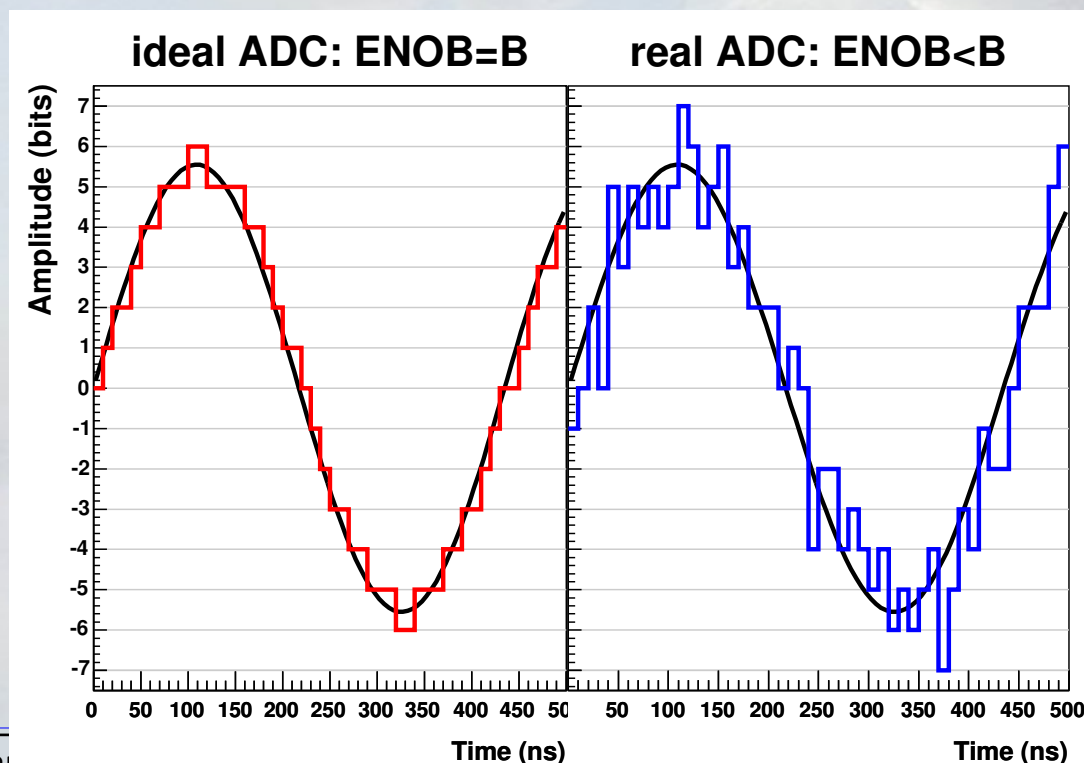


digital filter:
semigaussian,
trapezoidal,
triangular,
optimal...

Sampling frequency “ f_s ” Limits the bandwidth of the system

Number of bits “ B ” quantization level

Effective number of bits “ $ENOB$ ” Real ADCs have thermal noise, ...
 $ENOB$ gives the ADC noise performances in terms of an equivalent “ideal” ADC:



The **same quan-
tization** level, but
much more noise

In the figure:

$$B = 12$$

$$ENOB = 10.6$$

(typical values)

One can carry out the computation and compare the result with the peak-sensing expression:

$$\frac{\sigma_{\text{exp}}^2}{\sigma_{\text{th}}^2} = 1 + \frac{9}{12} \left(\frac{R}{3\sigma_{\text{th}}} \right)^2 \cdot \frac{1}{4^{\text{PSENOB}}}$$

with the definition

$$\text{PSENOB} = \text{ENOB} + \frac{1}{2} \log_2 \left(\frac{f_S \tau_C}{k_G^2} \right) - \frac{1}{2}$$

PPeak-**S**ensing-**E**quivalent **N**umber **o**f **B**its

- depends on the ADC ENOB value
- depends logarithmically on $f_S \cdot \tau_C$ (detector corner time)
- depends on the used filter G with k_G ($\simeq 1$ for common filters)

details in: L.Bardelli and G.Poggi, NIM A560 (2006) 517 and 524

$$\text{PSENOB} = \text{ENOB} + \frac{1}{2} \log_2 \left(\frac{f_S \tau_C}{k_G^2} \right) - \frac{1}{2}$$

Some numerical examples (using $\tau_C = 5\mu s$):

| ENOB Bits | | f_S (MS/s) | PSENOB |
|-----------|----|--------------|--------|
| 12.0 | 14 | 100 | 16.2 |
| 10.0 | 12 | 400 | 15.3 |
| 10.8 | 12 | 100 | 15.0 |
| 10.0 | 12 | 200 | 14.7 |
| 7.0 | 8 | 2000 | 13.4 |

Modern fast sampling ADCs → **wide dynamic ranges!**

details in: L.Bardelli and G.Poggi, NIM A560 (2006) 517 and 524

timing

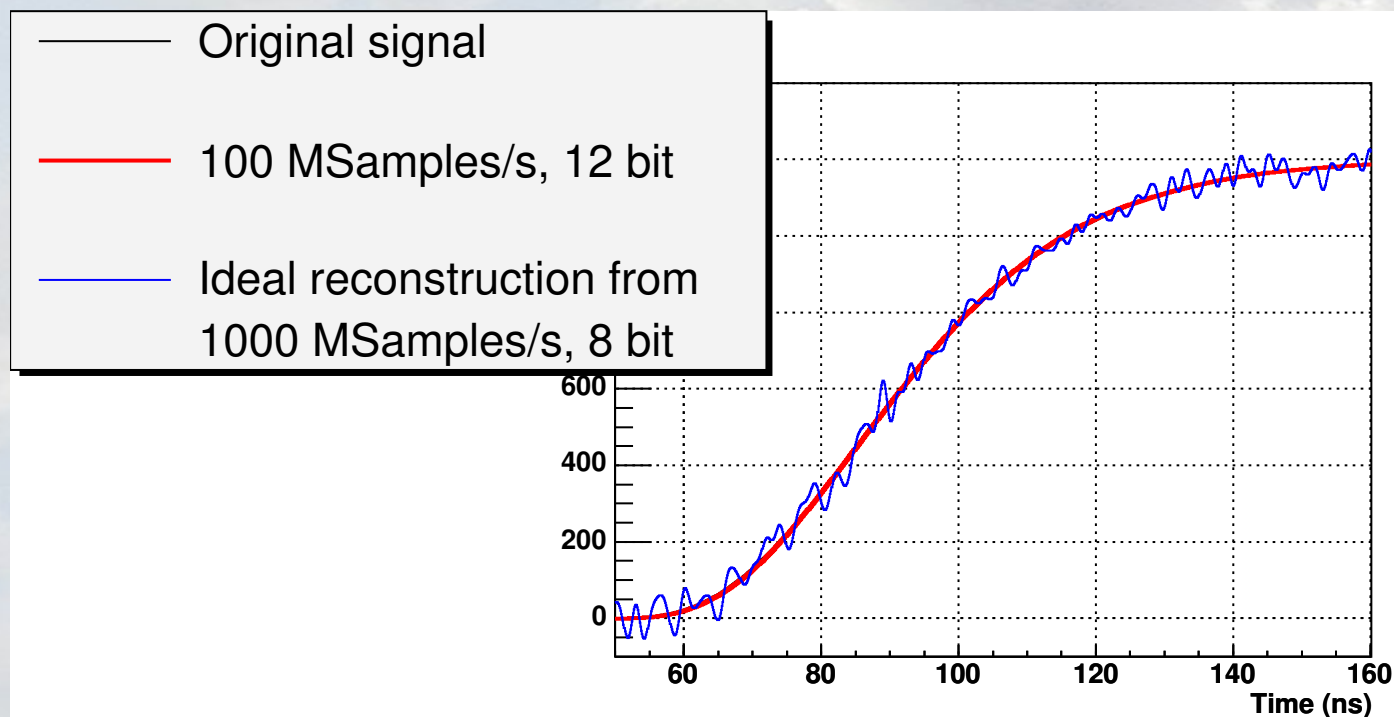


High resolution or High speed Sampling ADC?

High resolution or High speed Sampling ADC?

Timing measurements: in practice obtain the time t_0 where $S(t_0) = S_0$

⇒ good timing possible with good signal reconstruction!



Key points for good signal reconstruction:

low noise

Higher speed = wider bandwidth = higher noise.

$f_{\text{sampling}} \approx f_{\text{Nyquist}}$ is enough...

good interpolation

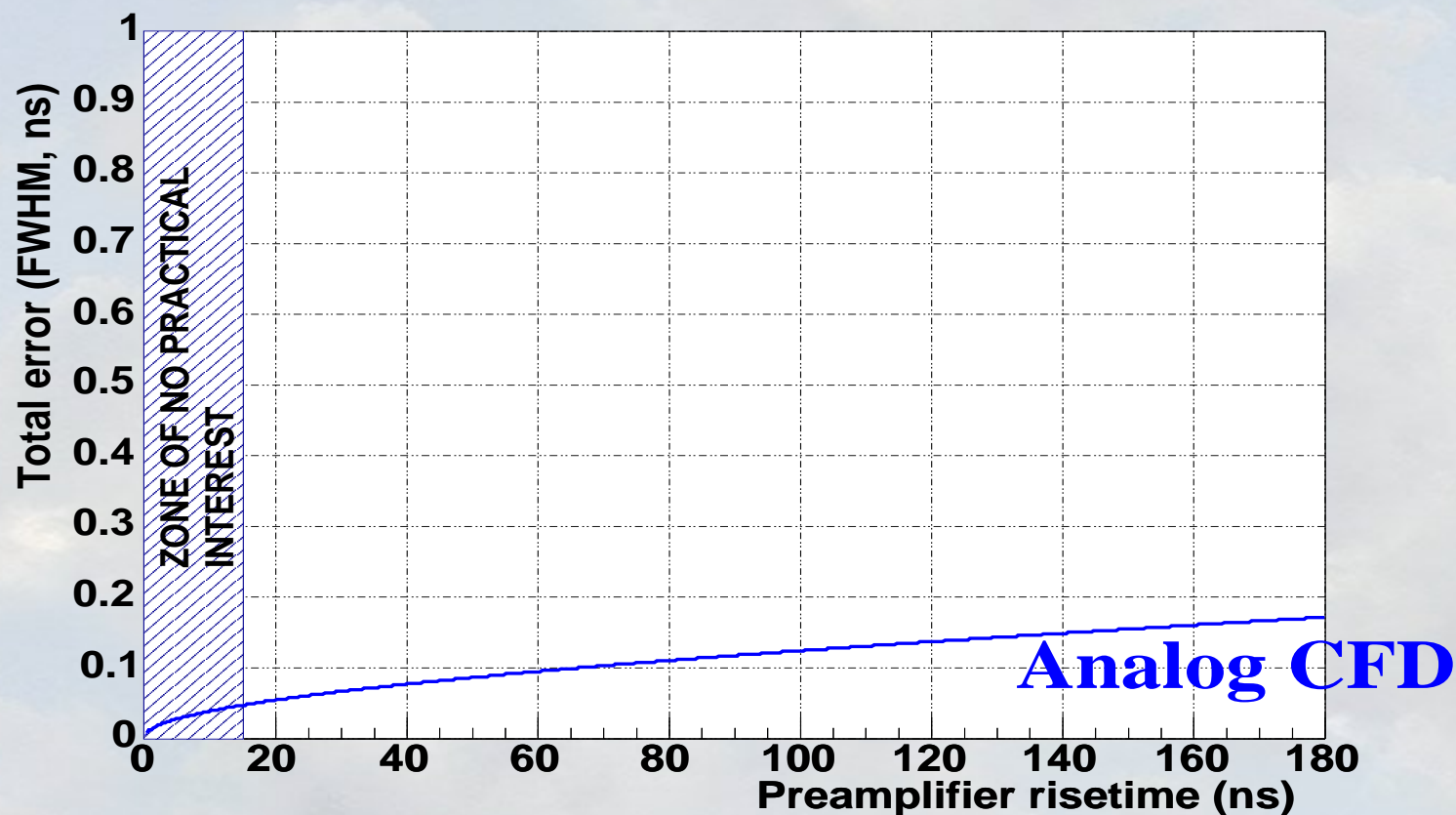
linear interpolation gives more error/noise

||  at least **cubic** is needed

Low noise + Good interpolation =
= Good Signal reconstruction = Good Timing!

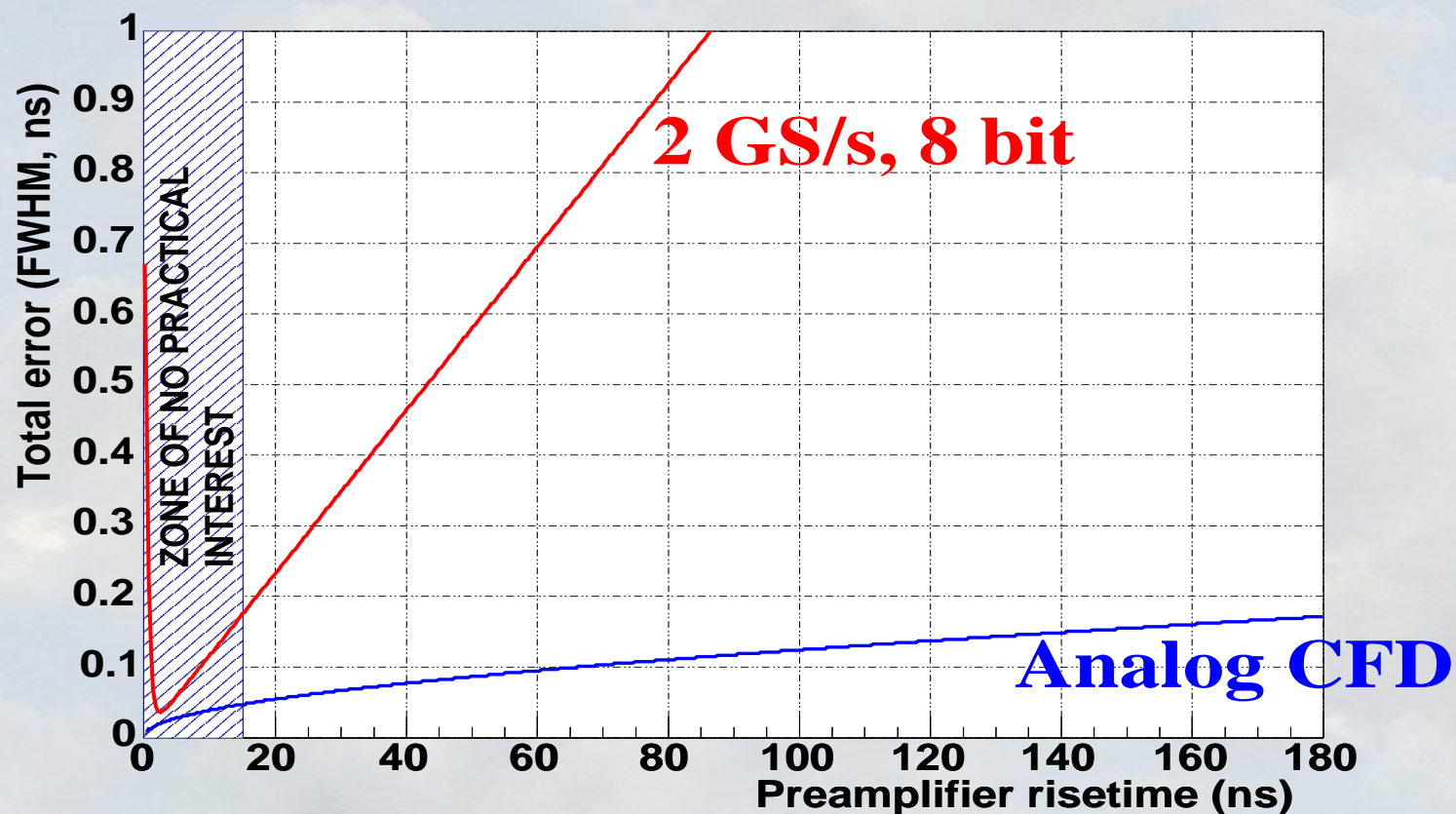
Which AD converter ? L.Bardelli *et al.*, NIM **A521** (2004)
realistic simulations, **fixed shape** signals, **cubic interpolation**:

dCFD timing ($f=0.2$)



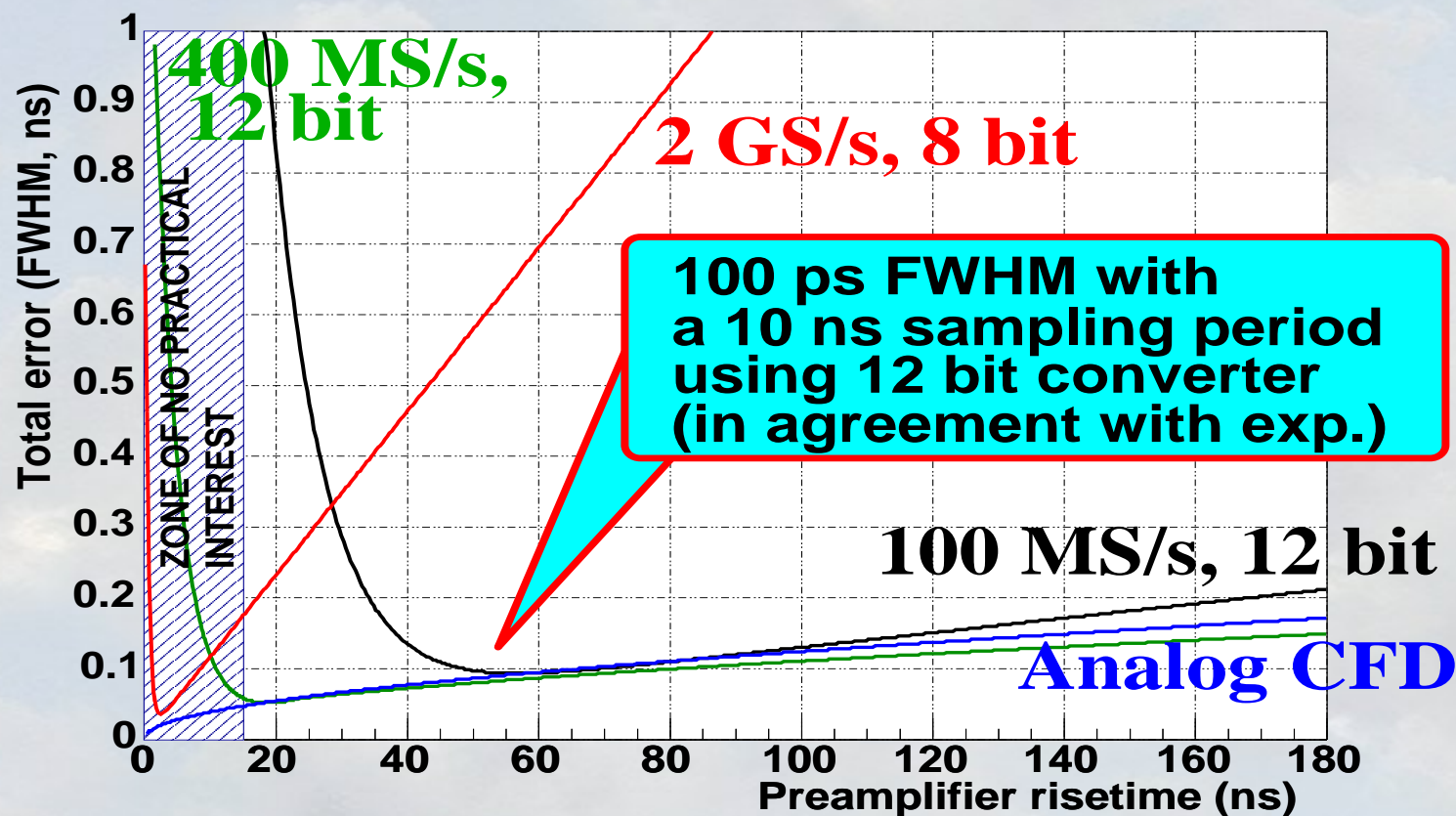
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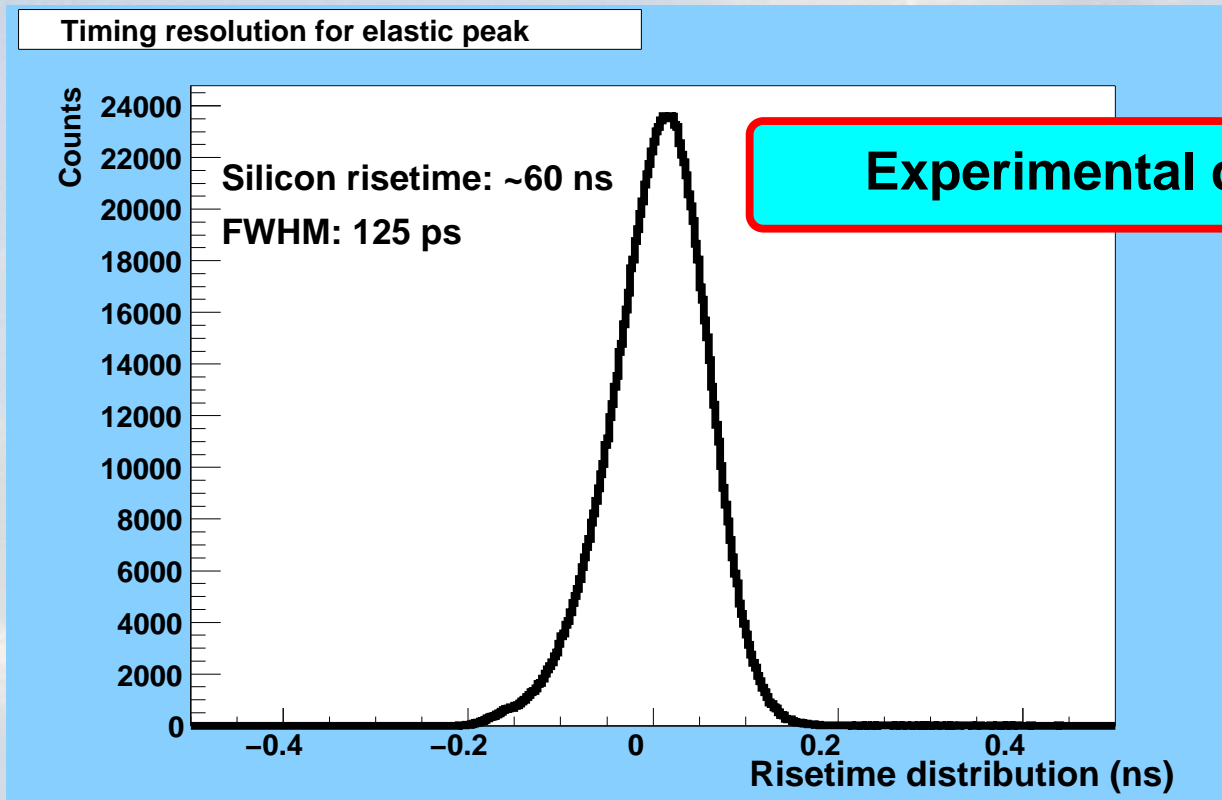
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dCFD timing ($f=0.2$)



12 bit \Rightarrow FWHM resolution 100 times smaller than sampling period

Rise-time analysis: differences between two **dCFDs**.
250 MeV Oxygen elastic peak using a Si detector (test at LNL)



reverse
380 μm ,
 $\approx 500 \text{ mm}^2$
Silicon

Time difference between 90% and 10% dCFDs
Cubic interpolation with 100 MS/s ADC

L.Bardelli *et al.*, NIM **A521** (2004)

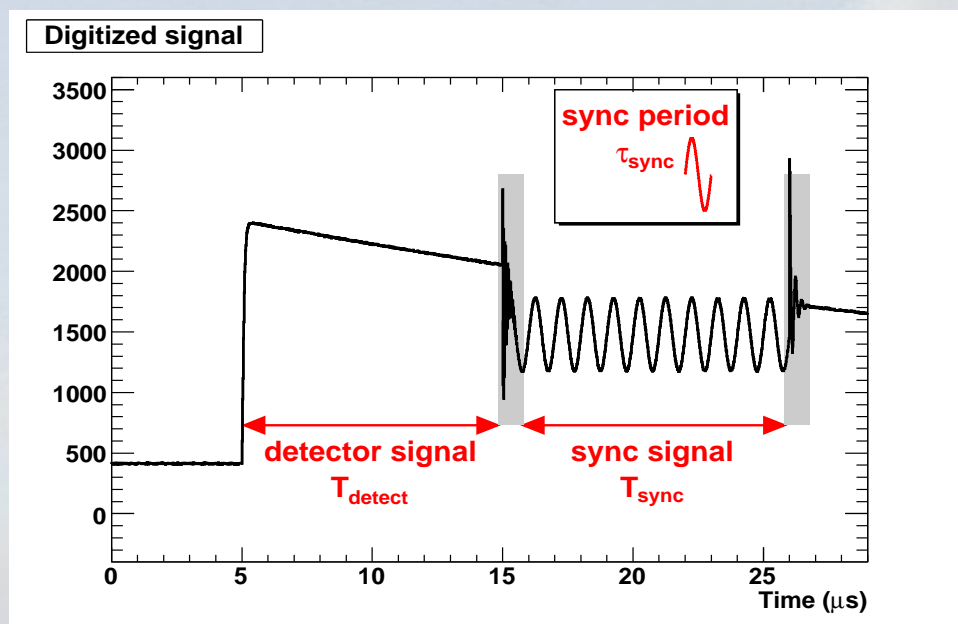
time of flight



Time of Flight or **coincidence** measurements?

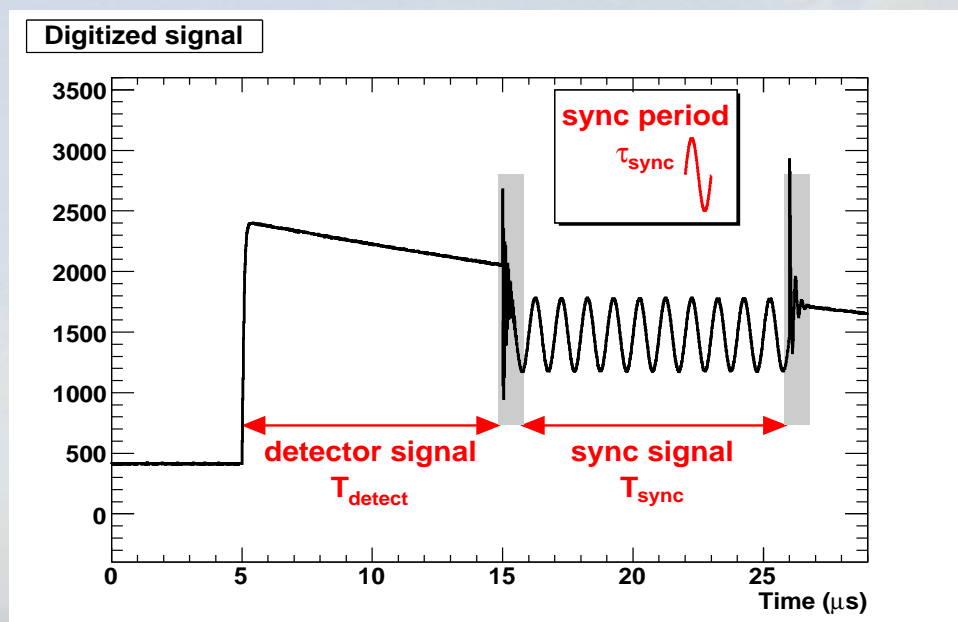
Time of Flight or **coincidence** measurements?

Time-stamped clock or **mix a common time reference signal with the preamplifier output**:



Time of Flight or **coincidence** measurements?

Time-stamped clock or **mix a common time reference signal with the preamplifier output**:



The DSP software can separate the "true" signal from the "reference" one and compute the time difference.

Using a train of pulses as reference the resolution can be significantly improved, down to **1 – 5 ps FWHM**

This allows for **synchronization** between many channels: **coincidence** measurements possible.

L.Bardelli *et al.*, NIM **A**, 572 (2007) pag 882

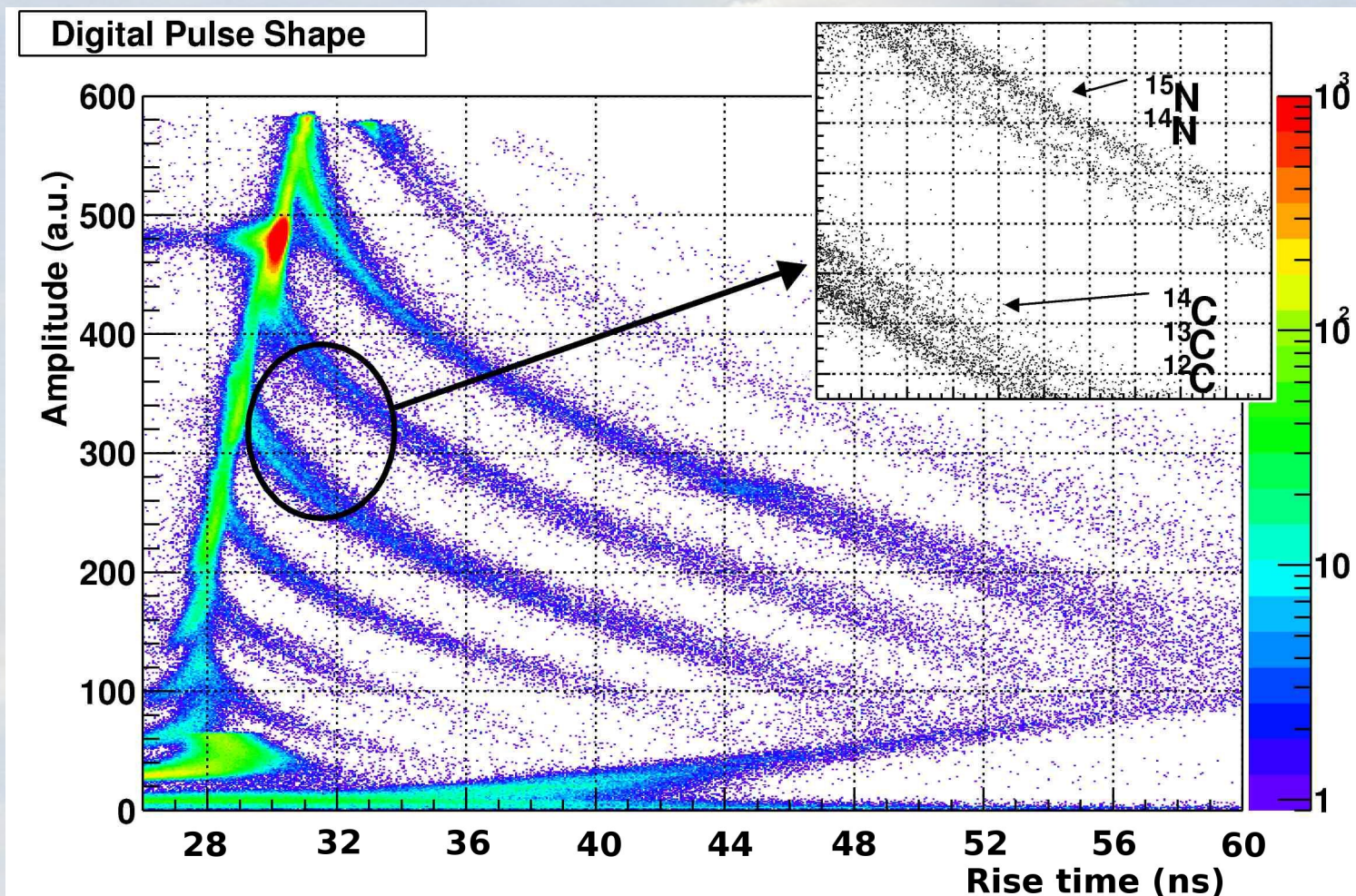
L.Bardelli *et al.*, NIM **A**, 521 (2004) pag 480

We have seen DIGITAL examples of:

- Signal Amplitude measurement (\Rightarrow energy)
- Timing measurement (\Rightarrow CFD, rise time)
- Inter-channel time synchronization (\Rightarrow ToF)

Now we can try an Energy vs “RiseTime” plot for a Silicon detector:

Digital Amplitude vs. **Digital Zero Crossing** time:



reverse
380 μm ,
 $\approx 500 \text{ mm}^2$
Silicon
12bit
100 MS/s
digitizer

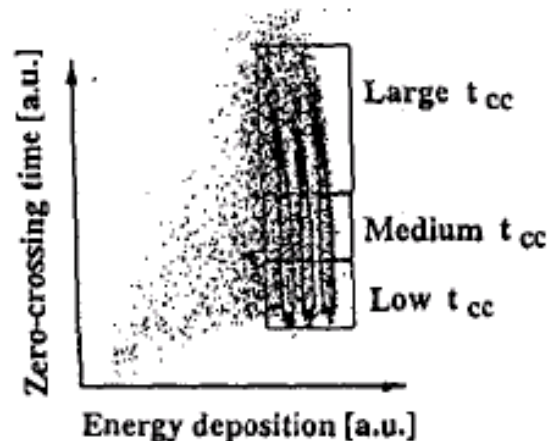
L.Bardelli *et al.*, NIM **A521** (2004)

Regardless of the analysis method, various factors may limit the achievable identification performances, like:

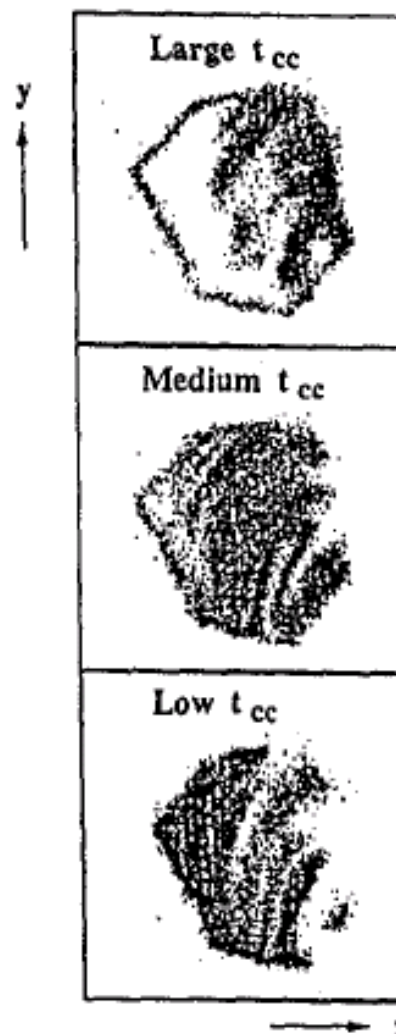
- Detector thickness inhomogeneities
- Detector bias voltage
- Thresholds
- Channeling effects

... let's see some examples

a) t_{cc} gates:



b) Maps of a single detector:



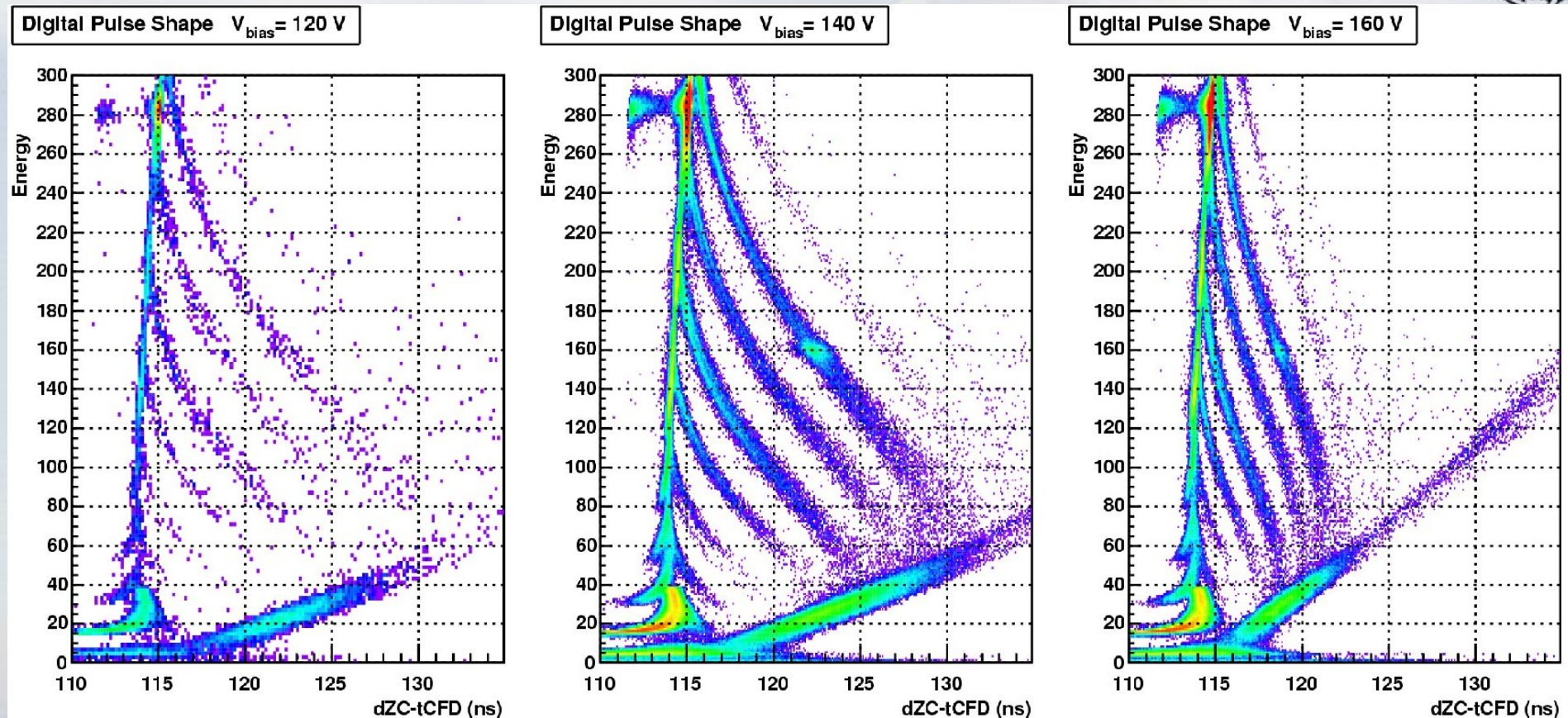
c) Combined maps of detectors from a single Si wafer (medium t_{cc}):



G.Pausch *et al.*, IEEE Trans. Nucl. Science, vol.44, no.3, June 1997

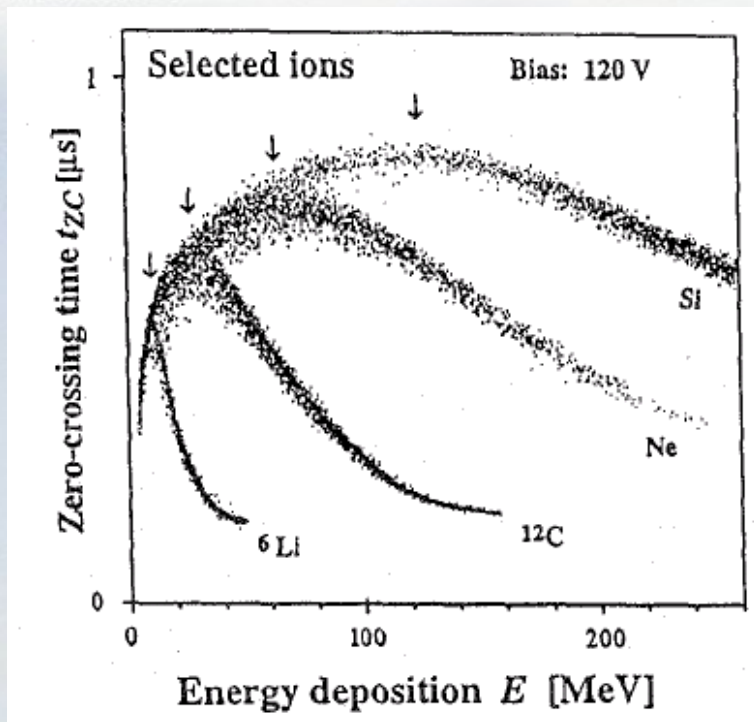
the detector area and uniformity are important!

Additional tests will be performed by the FAZIA collaboration at LNL in the first week of June.



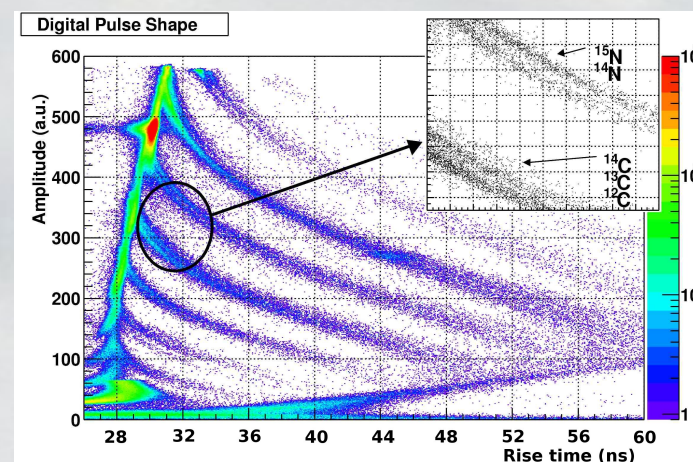
- detector bias/depletion voltage need careful optimization
- during experiment the detector bias must be monitored

L.Bardelli, PhD Thesis, Florence, 2005



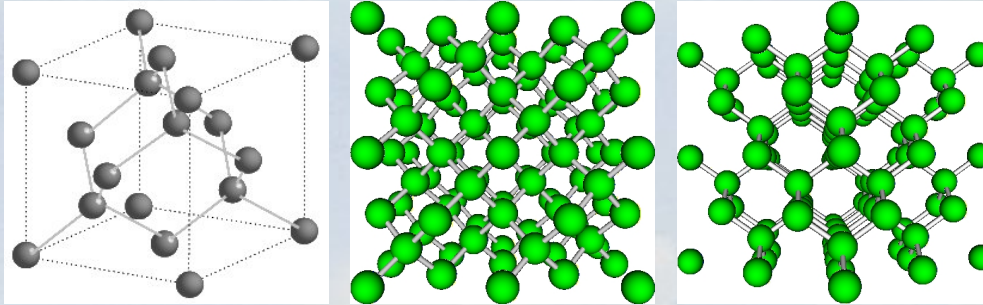
G.Pausch *et al.*, IEEE Trans. Nucl. Science, vol.44, no.3, June 1997

All the “identification” lines merge into a single line: this effect can be explained in terms of “plasma” effects, see L.Bardelli *et al*, Proc. of IWM2005 conf., ISBN 88-7438-029-1



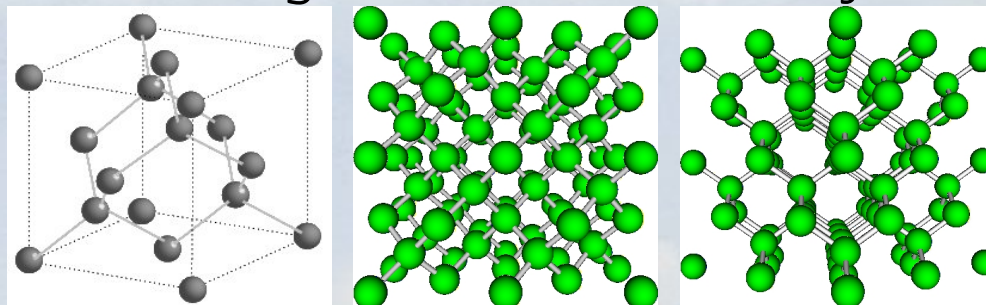
About **30 μm** Si-equivalent for LNL2002 dataset.

Channeling effects can destroy the PSA resolution:

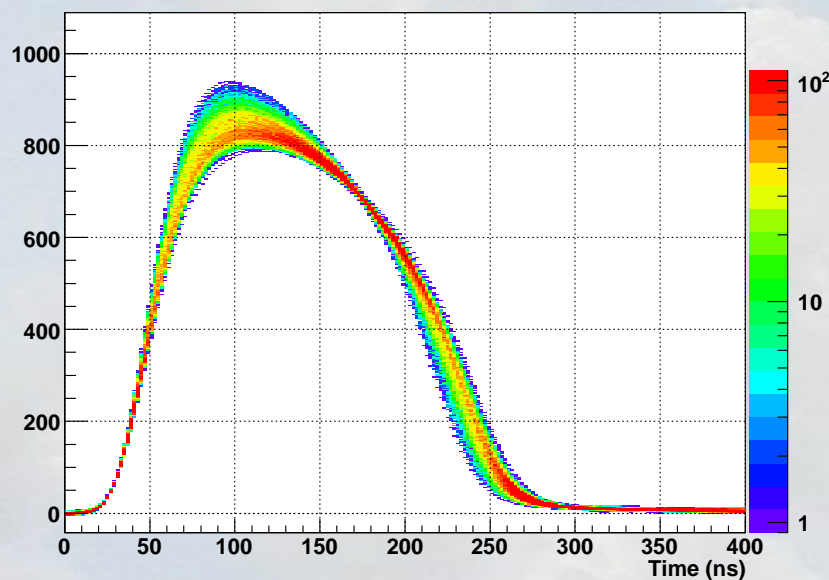


→ our detectors??

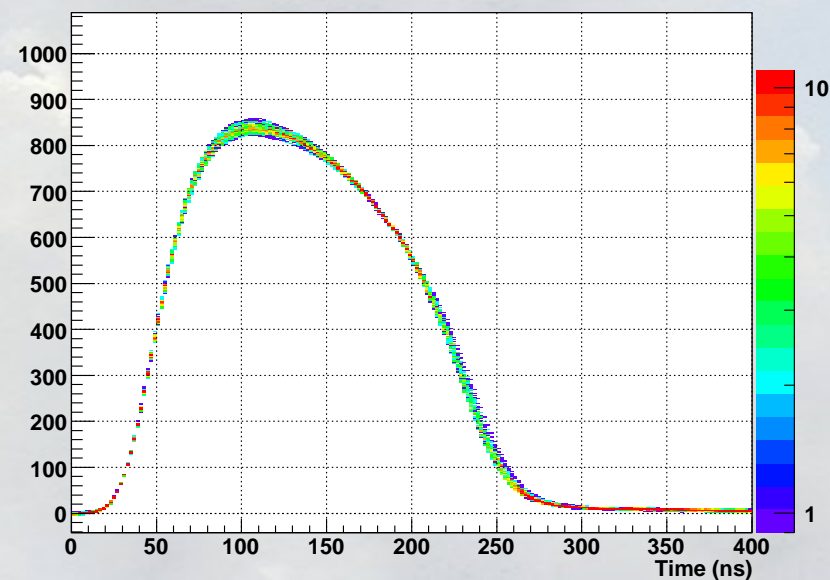
Channeling effects can destroy the PSA resolution:



→ our detectors??



Channeled



Random ($\sim 9^\circ$)

$i(t)$, ^{80}Se @ 408 MeV, $\langle 100 \rangle$

L. Bardelli et al., LNL Ann.rep.2006 & in preparation

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1. dedicated working group (WG1)

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7. Strip detectors?

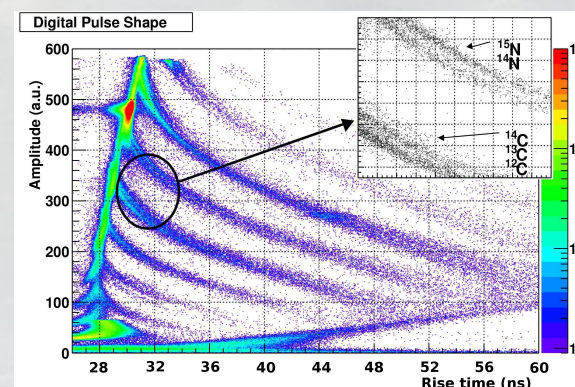
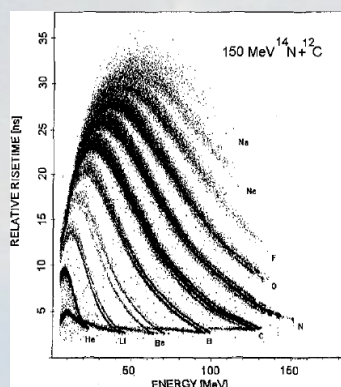
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5. Which algorithm? new algorithms are under study
6. Which frontend? development system with fast/slow sampling and realtime analysis (G.Pasquali, P.Edelbruck, et al)
7. Strip detectors?
8. Channeling/homogeneity? tests are in progress (L.Bardelli et al)

The FAZIA collaboration is currently performing an R&D activity on digital pulse shape analysis in Silicon Detectors:

1. dedicated working group (WG1)
2. a number of experimental tests for building a signal database (mainly for heavy ions)
3. PACI preamp to compare $q(t)$ and $i(t)$ → H.Hamrita et al.
4. Which digitizer? Low speed/high resolution or High speed/low resolution? (MAR ASIC, S.Drouet et al)
5. Which algorithm? new algorithms are under study
6. Which frontend? development system with fast/slow sampling and realtime analysis (G.Pasquali, P.Edelbruck, et al)
7. Strip detectors?
8. Channeling/homogeneity? tests are in progress (L.Bardelli et al)
9. Detector simulations are in progress (L.Bardelli et al)

- PSA in silicon detectors may be used to significantly lower the detection and particle identification thresholds
- Digital sampling methods offer a powerful and compact way to realize such systems
- Proper algorithms make high-resolution digital energy and timing measurements possible
- PSA resolution may be limited by detector properties



Some references: M.Mutter, IEEE.T.N.S.47, L.B. NIMA572, G.Pasquali NIMA570, L.B. NIMA560, L.B. NIMA521, L.B. NPA746, L.B. NIMA491, <http://fazia.in2p3.fr>

